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DOCKET NO.: 218125US2

IN THE UNITED STATES PATENT & TRADEMARK OFFICE

IN RE APPLICATION OF

KEUI NAKAYAMA, ET AL.

: EXAMINER: ALLEN, A. J.

NC. 586

SERIAL NO: 10/044,956

FILED: JANUARY 15, 2002

: GROUP ART UNIT: 2855

FOR:

METHOD OF AND APPARATUS

FOR MEASURING AND EVALUATING MATERIAL STRENGTH BY DETECTING CHARGED PARTICLES

AMENDMENT

ASSISTANT COMMISSIONER FOR PATENTS WASHINGTON, D.C. 20231

SIR:

In response to the Official Action mailed October 17, 2002, please amend this application as follows:

IN THE CLAIMS

Please amend Claims 1-10 as follows:

Claim 1. (Currently Amended) A material strength measuring and evaluating method for measuring and evaluating at least one of a peel strength and/or and a fragility breaking strength of a fragile thin film, said method being earried out by detecting charged particles and comprising the steps of:

pressing an indenter into a test object and measuring an indentation load as well as and an indentation depth, while at the same time detecting charged particles emitted from a peel starting point or a breakage starting point;

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